

Notice of References Cited	Application/Control No. 10/784,112		Applicant(s)/Patent Under Reexamination LIAO ET AL.	
	Examiner Kevin K. Xu		Art Unit 2628	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0126133	09-2002	Ewins, Jon P.	345/587
*	B	US-5,740,344	04-1998	Lin et al.	345/587
*	C	US-6,184,894	02-2001	Rosman et al.	345/582
*	D	US-6,353,438	03-2002	Van Hook et al.	345/552
*	E	US-2005/0128213	06-2005	Barenbrug et al.	345/587
*	F	US-2004/0119720	06-2004	Spangler, Steven J.	345/583
*	G	US-2001/0048443	12-2001	Burrell, Jeffrey	345/582
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ewins, Jon "Mip-Map Level selection for Texture Mapping". October-December1998, Vol 4, p. 317-329
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.